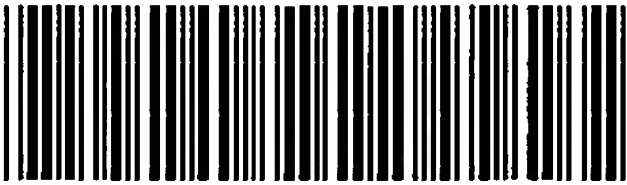


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/670,380	LEE, SANG-HYUK	
	Examiner	Art Unit	
	Tai Duong	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	40	7/24/2006	TD
	187		
	192		
324	770		
438	30		
445	24		
	25		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US PGPUB, USPAT, EPO, JPO, DERWENT, IBM TDB) see search history printout	7/24/2006	TD